

# Supporting Information

## Network Former Mixing (NFM) Effects in Alkali Germanotellurite Glasses.

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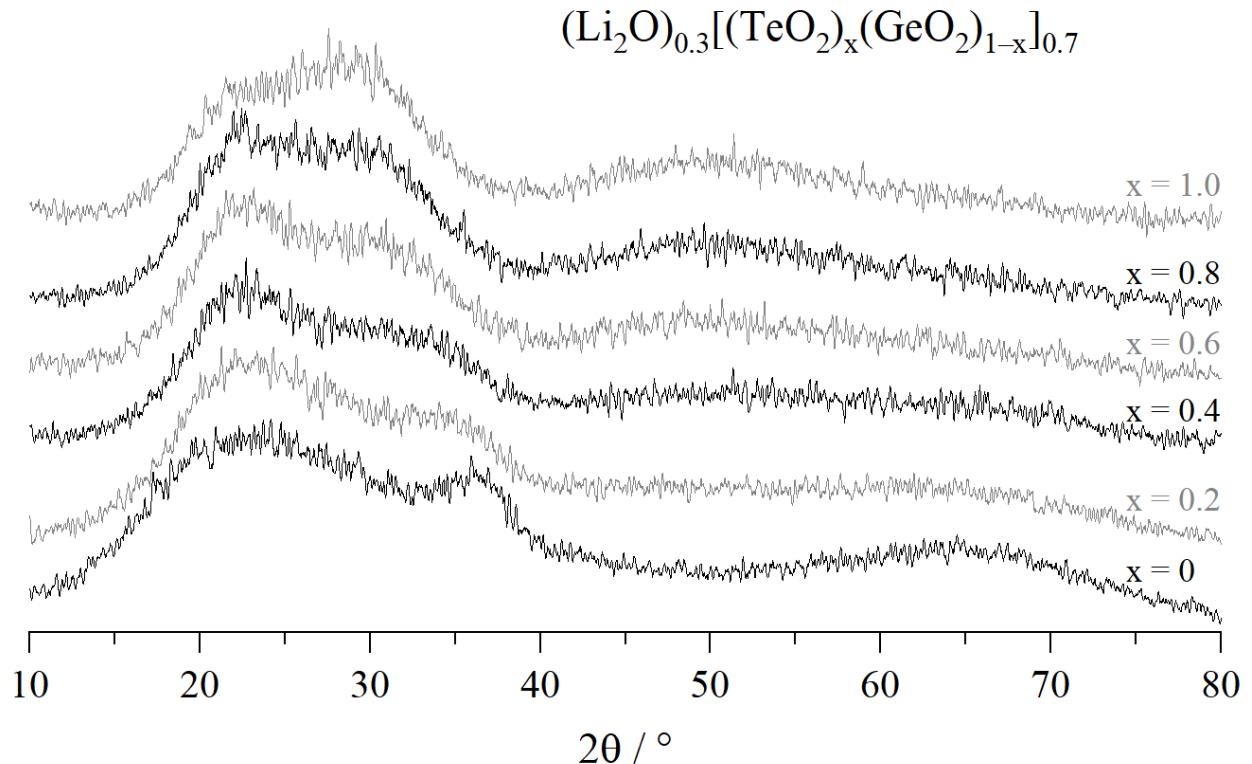
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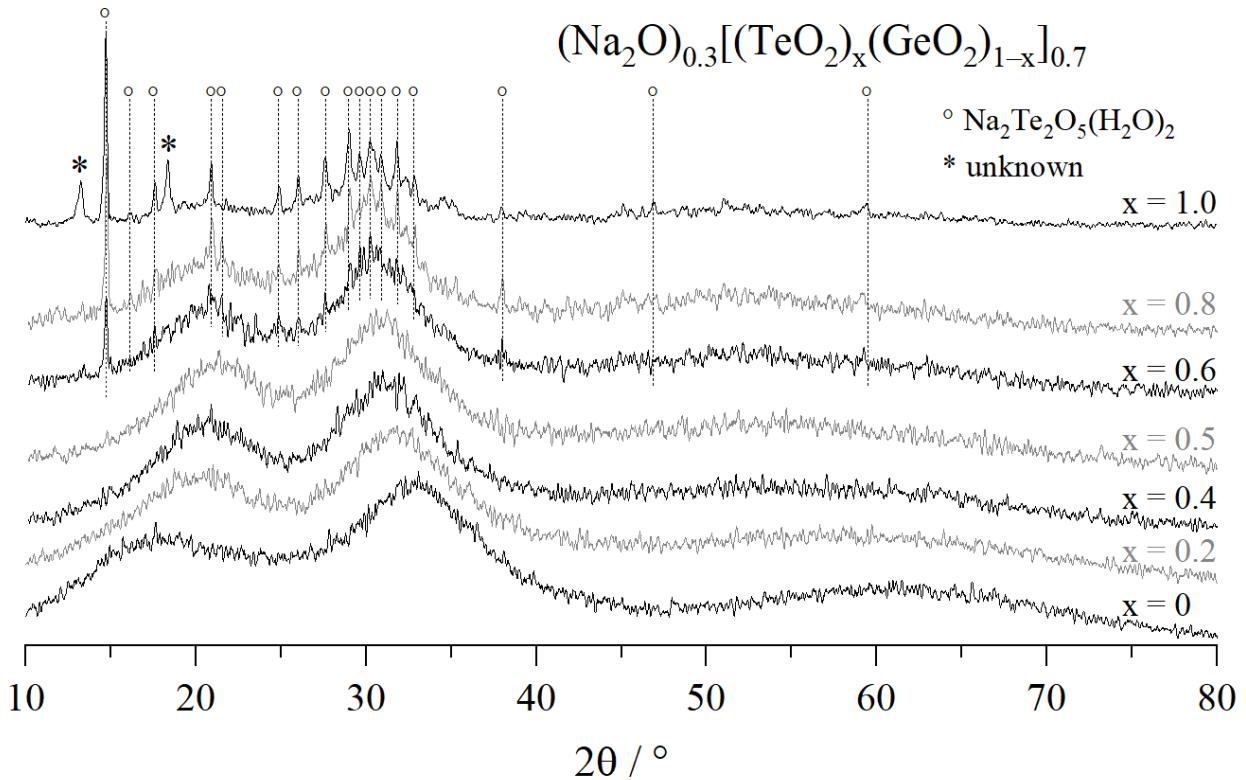
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**Table S1** – Nominal chemical compositions (nom.) of the  $(A_2O)_{0.3}[(TeO_2)_x(GeO_2)_{1-x}]_{0.7}$  ( $A = Li, Na$ ) glass samples and those measured by ICP-OES, XRF and EDS.  $TeO_2$  and  $GeO_2$  contents determined by XRF and EDS for the  $A = Li$  glasses were normalized assuming the respective  $Li_2O$  contents from ICP-OES or the nominal ones when the latter method was not applied. All the values are given in mass percent (m%). The errors are 0.5, 1 and 2 m% for ICP-OES, XRF and EDS respectively.

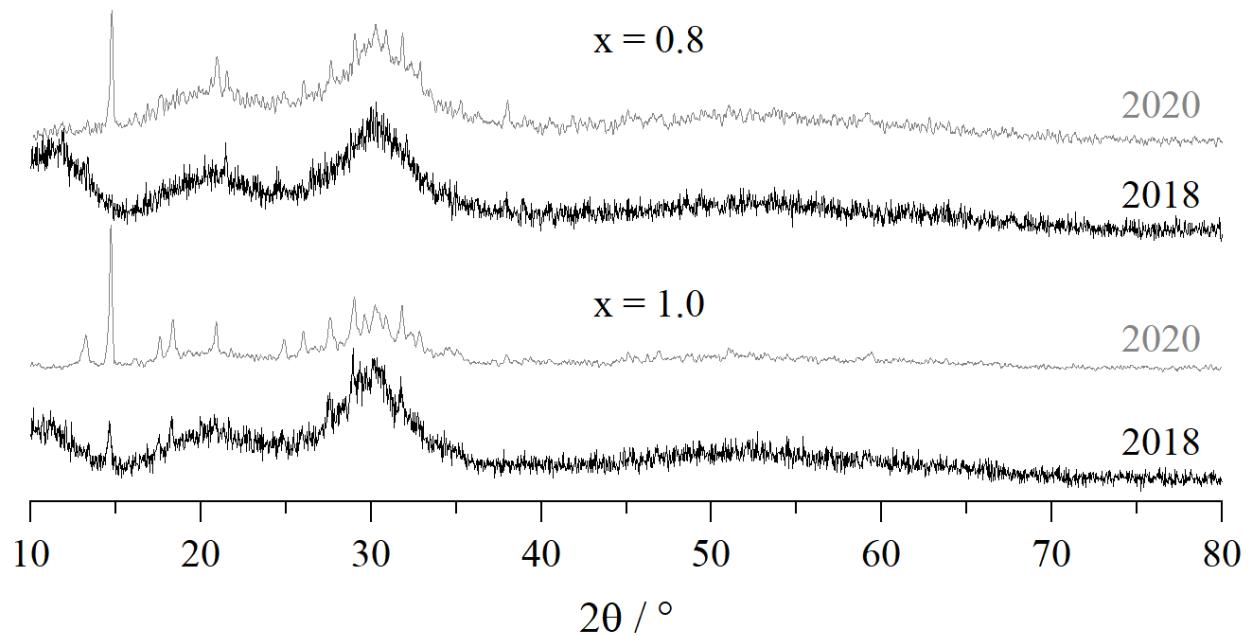
Composition	m%( $A_2O$ )				m%( $TeO_2$ )			m%( $GeO_2$ )			
	nom.	XRF	EDS	ICP-OES	nom.	XRF	EDS	Nom.	XRF	EDS	
$A = Li$	$x = 0.0$	10.9	-	-	11.1	0.0	0.0	0.0	89.1	90.0	90.0
	$x = 0.2$	10.0	-	-	n.A.	24.9	23.4	25.1	65.2	67.6	65.8
	$x = 0.4$	9.2	-	-	9.7	45.8	44.4	46.7	45.0	46.8	44.4
	$x = 0.5$	8.8	-	-	n.A.	55.1	54.4	57.1	36.1	37.5	34.8
	$x = 0.6$	8.5	-	-	7.9	63.7	63.8	65.1	27.8	28.8	27.5
	$x = 0.8$	7.9	-	-	n.A.	79.1	78.9	79.5	13.0	13.7	13.1
	$x = 1.0$	7.4	-	-	7.1	92.6	93.3	93.3	0.0	0.0	0.0
$A = Na$	$x = 0.0$	20.2	n.A.	14.6	-	0.0	n.A.	0.0	79.8	n.A.	85.4
	$x = 0.2$	18.7	13.4	15.3	-	22.4	22.0	22.7	58.9	64.6	62.1
	$x = 0.4$	17.3	14.1	14.2	-	41.7	43.9	42.4	41.0	42.0	43.4
	$x = 0.5$	16.7	15.1	n.A.	-	50.3	46.7	n.A.	33.0	38.2	n.A.
	$x = 0.6$	16.2	13.5	12.2	-	58.3	61.0	62.2	25.5	25.5	25.7
	$x = 0.8$	15.2	11.6	16.2	-	72.9	78.6	74.2	11.9	9.8	9.6
	$x = 1.0$	14.3	12.3	12.4	-	85.7	87.7	87.5	0.0	0.0	0.0



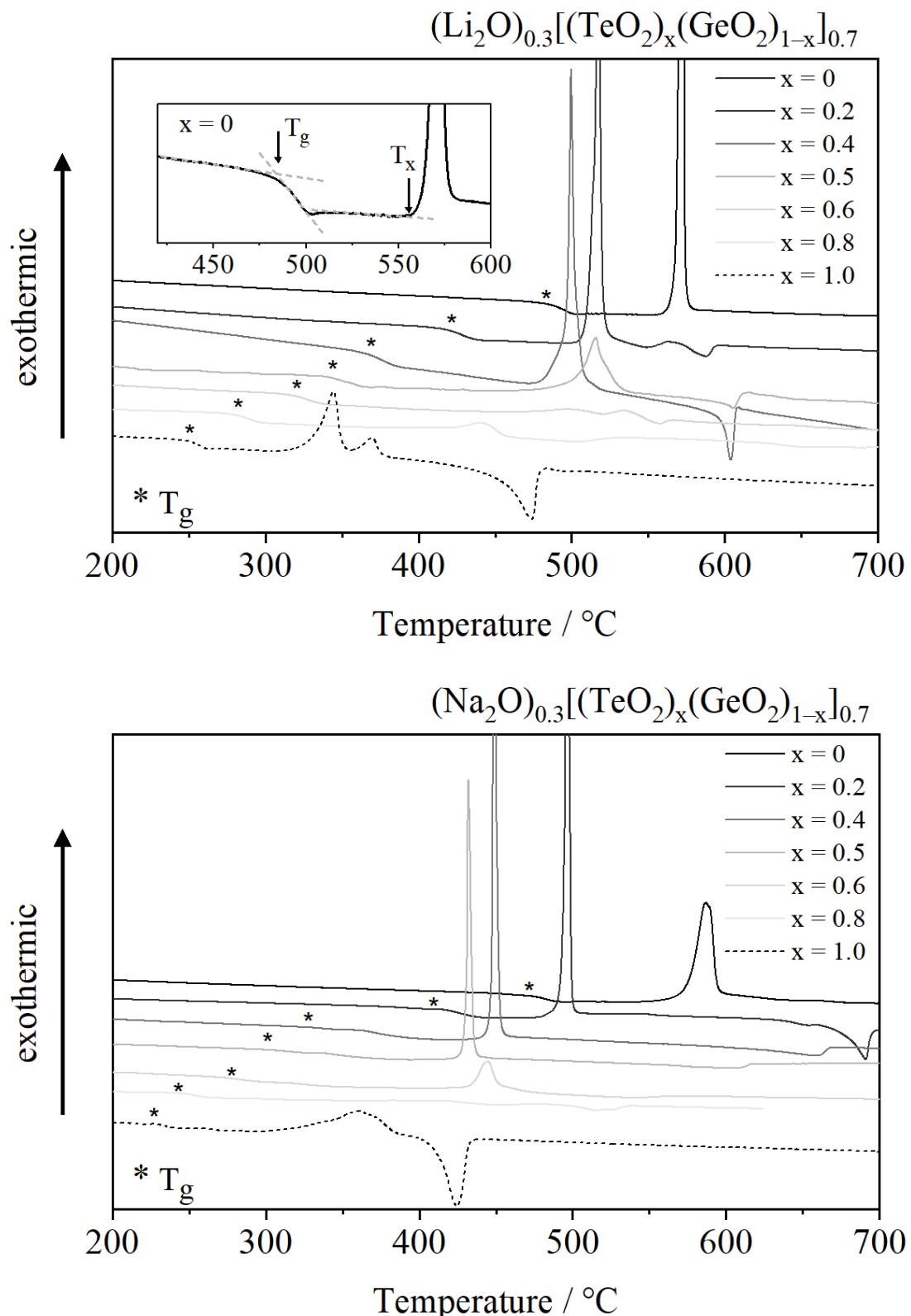
**Figure S1:** Powder X-ray diffractograms of  $(Li_2O)_{0.3}[(TeO_2)_x(GeO_2)_{1-x}]_{0.7}$  glasses.



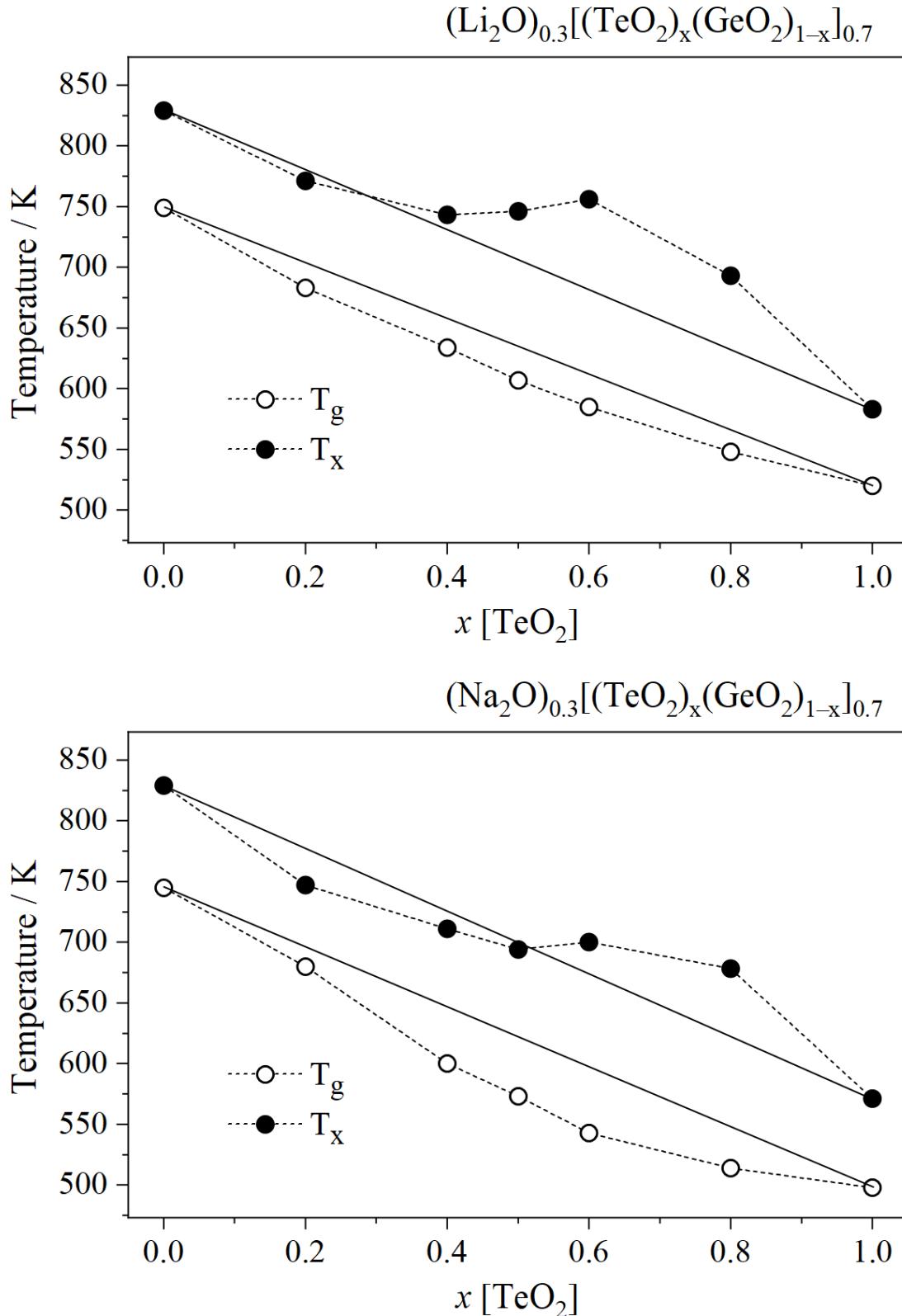
**Figure S2:** Powder X-ray diffractograms of  $(\text{Na}_2\text{O})_{0.3}[(\text{TeO}_2)_x(\text{GeO}_2)_{1-x}]_{0.7}$  glasses. Asterisks, circles, and dashed vertical lines indicate diffraction bands attributable to crystalline phases found with help of the Qualx2 software[1] using the crystallography open database (COD).[2]



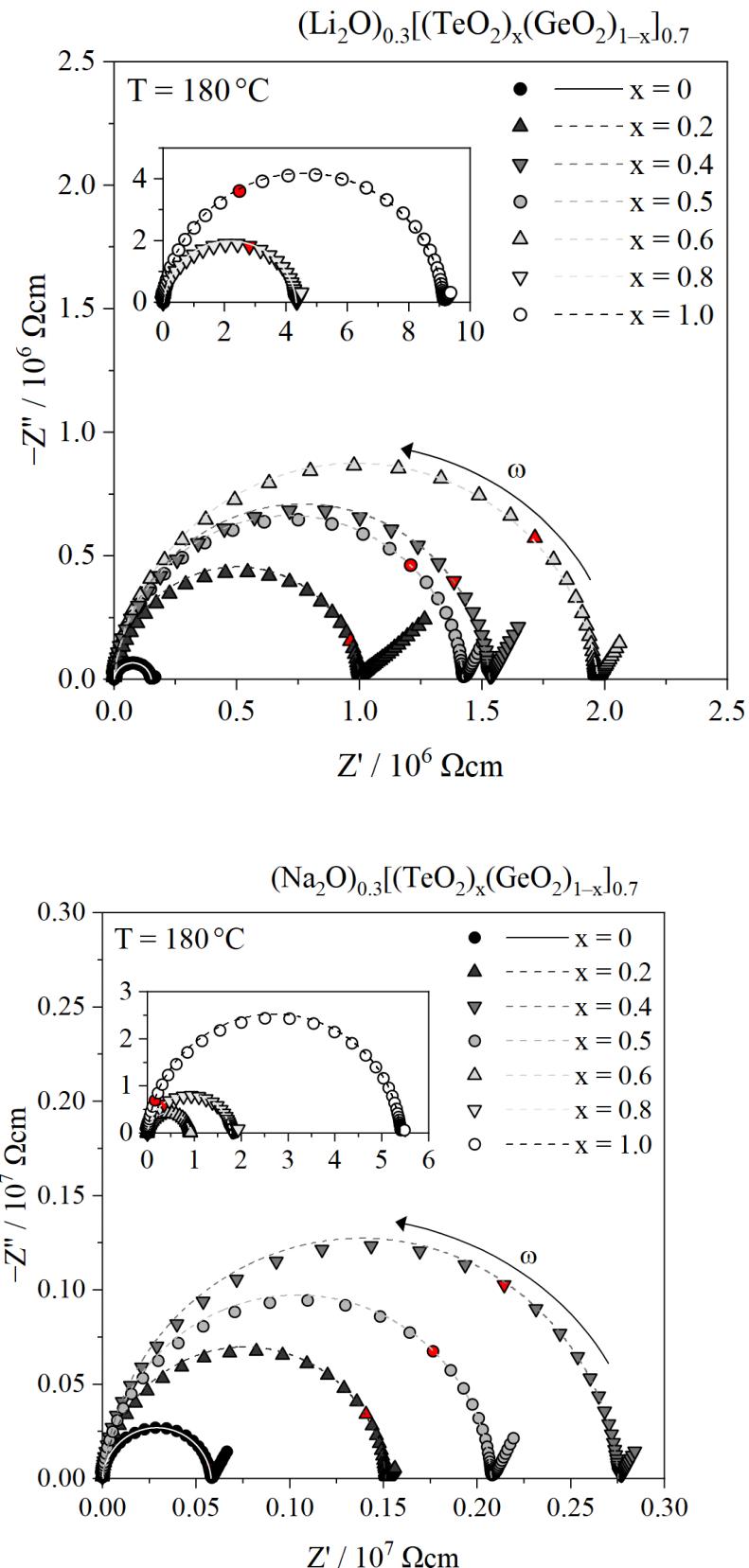
**Figure S3:** Comparison of powder X-ray diffractograms of  $(Na_2O)_{0.3}[(TeO_2)_x(GeO_2)_{1-x}]_{0.7}$  glasses with  $x = \{0.8;1.0\}$ , recorded shortly after preparation (2018) and two years later (2020). Visible diffraction bands are attributable to  $Na_2Te_2O_5(H_2O)_2$  (see also Figure S2).



**Figure S4:** DSC curves of  $(\text{A}_2\text{O})_{0.3}[(\text{TeO}_2)_x(\text{GeO}_2)_{1-x}]_{0.7}$  ( $\text{A} = \text{Li}, \text{Na}$ ) glasses. The inset (top) shows exemplarily the extraction of characteristic temperatures  $T_x$  and  $T_g$  (indicated by asterisks).



**Figure S5:** Characteristic temperatures  $T_x$  and  $T_g$  of  $(\text{A}_2\text{O})_{0.3}[(\text{TeO}_2)_x(\text{GeO}_2)_{1-x}]_{0.7}$  ( $\text{A} = \text{Li}, \text{Na}$ ) glasses against glass composition  $x$ . Solid lines serve as guide to the eye and connect the values of endmember compositions  $x = 0$  ( $(\text{A}_2\text{O})_{0.3}(\text{GeO}_2)_{0.7}$ ) and  $x = 1$  ( $(\text{A}_2\text{O})_{0.3}(\text{TeO}_2)_{0.7}$ ).



**Figure S6:** Complex plane plot of impedance data of  $(\text{A}_2\text{O})_{0.3}[(\text{TeO}_2)_x(\text{GeO}_2)_{1-x}]_{0.7}$  ( $\text{A} = \text{Li}, \text{Na}$ ) glasses recorded at  $180^\circ\text{C}$ . Red data points indicate a frequency of  $10 \text{ kHz}$ . The solid and dashed lines indicate least-squares fits to the data according to the semi-circle function  $y = -(y_0 + (r^2 - (x-x_0)^2)^{1/2})$ , where  $x_0$  and  $y_0$  represent offsets on the  $Z'$  and  $Z''$  axes respectively, and  $r$  represents the radius of the semi-circle. Data are divided by the geometrical factor  $1/S$  ( $l$  = sample thickness,  $S$  = area of the electrode), so the non-trivial zero of the fit function then corresponds to the real resistivity value, used to calculate the conductivity shown in the Arrhenius plots in Figure 1.

## References

- [1] Altomare, A., Corriero, N., Cuocci, C., Falcicchio, A., Moliterni, A., Rizzi, R., QUALX2.0: a qualitative phase analysis software using the freely available database POW\_COD, *J. Appl. Cryst.* 48 (2015). 598-603.
- [2] Grazulis, S., Chateigner, D., Downs, R. T., Yokochi, A. T., Quiros, M., Lutterotti, L., Manakova, E., Butkus, J., Moeck, P. & Le Bail, A., Crystallography Open Database – an open-access collection of crystal structures, *J. Appl. Cryst.* 42 (2009), 726-729.